

<HVIC>

# M81738FP

#### 1200V HIGH VOLTAGE HALF BRIDGE DRIVER

#### DESCRIPTION

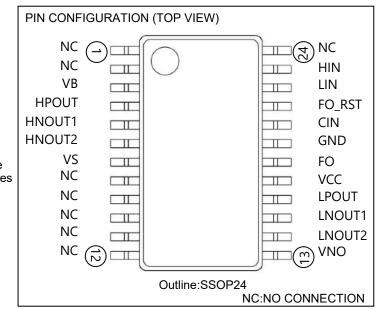
M81738FP is high voltage Power MOSFET and IGBT gate driver for half bridge applications.

#### **FEATURES**

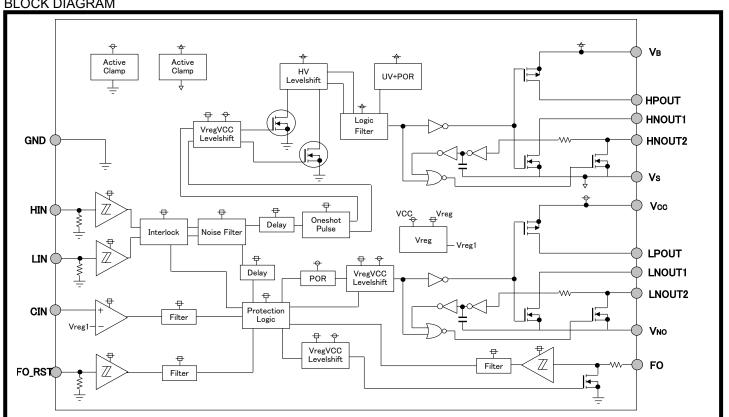
- •Floating supply voltage up to 1200V
- •Low quiescent power supply current
- •Separate sink and source current output up to ±1A (typ)
- Active Miller effect clamp NMOS with sink current up to 1A (typ)
- •Input noise filters (HIN,LIN,FO\_RST,FO)
- Over-current detection and output shutdown
- High side under voltage lockout
- •FO pin which can input and output Fault signals to communicate with controllers and synchronize the shut down with other phases
- Active clamp (power supply surge clamp)
- •24-Lead SSOP PACKAGE

#### **APPLICATIONS**

Power MOSFET and IGBT gate driver for Medium and Micro inverter or general purpose.



#### **BLOCK DIAGRAM**



# M81738FP

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#### **ABSOLUTE MAXIMUM RATINGS**

Absolute maximum ratings indicate limitation beyond which destruction of device may occur. All voltage parameters are absolute voltage reference to GND unless otherwise specified.

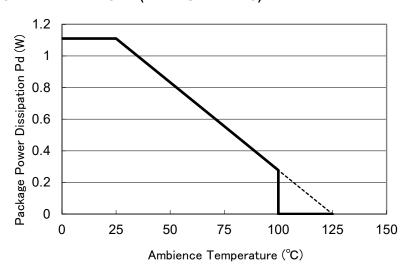
Symbol	Parameter	Test conditions	Ratings	Unit	
V <sub>B</sub>	High side floating supply absolute voltage		-0.5 ~ 1224	V	
Vs	High side floating supply offset voltage		V <sub>B</sub> -24 ~ V <sub>B</sub> +0.5	V	
V <sub>BS</sub>	High side floating supply voltage	V <sub>BS</sub> =V <sub>B</sub> -V <sub>S</sub>	-0.5 ~ 24	V	
V <sub>HO</sub>	High side output voltage		V <sub>S</sub> -0.5 ~ V <sub>B</sub> +0.5	V	
V <sub>CC</sub>	Low side fixed supply voltage		-0.5 ~ 24	V	
V <sub>NO</sub>	Power ground		V <sub>CC</sub> -24 ~ V <sub>CC</sub> +0.5	V	
$V_{LO}$	Low side output voltage		$V_{NO}$ -0.5 ~ $V_{CC}$ +0.5	V	
V <sub>IN</sub>	Logic input voltage	HIN, LIN, FO_RST	-0.5 ~ V <sub>CC</sub> +0.5	V	
$V_{FO}$	FO input/output voltage		-0.5 ~ V <sub>CC</sub> +0.5	V	
V <sub>CIN</sub>	CIN input voltage		-0.5 ~ V <sub>CC</sub> +0.5	V	
dV <sub>S</sub> /dt	Allowable offset voltage slew rate	V <sub>S</sub> -GND	±50	V/ns	
Pd	Package power dissipation	Ta= 25°C ,On our standard PCB	~ 1.11	W	
Kq	Linear derating factor	Ta≧25°C ,On our standard PCB	~ 11.1	mW/°C	
Rth(j-a)	Junction-ambient air thermal resistance	On our standard PCB	~ 90	°C/W	
Tj	Junction temperature		-40 ~ 125	°C	
Topr	Operation temperature		-40 ~ 100	°C	
Tstg	Storage temperature	On PCB	-40 ~ 150	°C	
TL	Solder reflow condition	Pb-free	255:10s, max260 °C		

#### **RECOMMENDED OPERATING CONDITIONS**

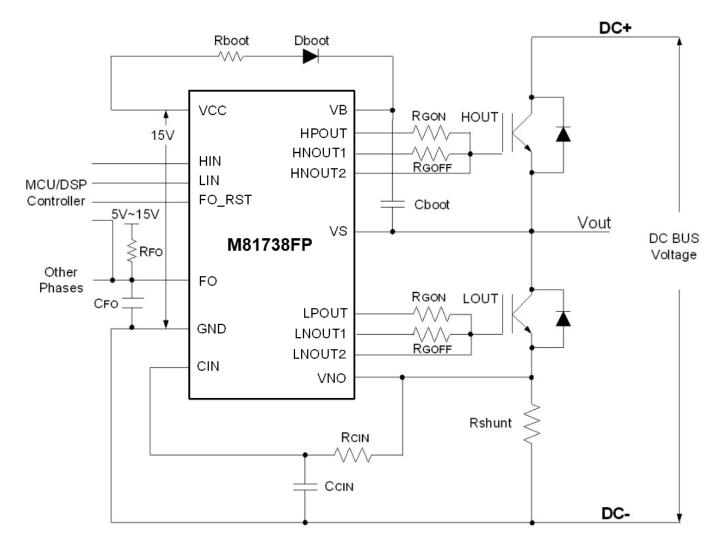
For proper operation the device should be used within the recommended conditions. All voltage parameters are absolute voltages referenced to GND unless otherwise specified.

Symbol	Parameter	Test conditions	Limits			Unit	
Symbol	Farameter	rest conditions	Min.	Тур.	Max.	Uill	
V <sub>B</sub>	High side floating supply absolute voltage		V <sub>s</sub> +13.5	V <sub>s</sub> +15	V <sub>s</sub> +20	V	
V <sub>s</sub>	High side floating supply offset voltage	V <sub>BS</sub> > 13.5V	-5	-	900	V	
$V_{BS}$	High side floating supply voltage	V <sub>BS</sub> =V <sub>B</sub> -V <sub>S</sub>	13.5	15	20	V	
$V_{HO}$	High side output voltage		V <sub>s</sub>	-	V <sub>s</sub> +20	V	
V <sub>CC</sub>	Low side fixed supply voltage		13.5	15	20	V	
$V_{NO}$	Power ground		-0.5	-	5	V	
VLO	Low side output voltage		$V_{NO}$	-	V <sub>CC</sub>	V	
V <sub>IN</sub>	Logic input voltage	HIN, LIN, FO_RST	0	-	V <sub>CC</sub>	V	
$V_{FO}$	FO input/output voltage		0	-	V <sub>CC</sub>	V	
V <sub>CIN</sub>	CIN input voltage		0	-	5	V	

### THERMAL DERATING FACTOR CHARACTERISTIC (MAXIMUM RATING)



#### **TYPICAL CONNECTION**



Note: If HVIC is working in high noise environment, it is recommended to connect a 1nF ceramic capacitor (CFO) to FO pin.

### M81738FP

#### 1200V HIGH VOLTAGE HALF BRIDGE DRIVER

ELECTRICAL CHARACTERISTICS (Ta=25°C, VCC=VBS (=VB-VS)=15V, unless otherwise specified) Limits Symbol Parameter Test conditions Unit Min. Тур. Max. High side leakage current  $V_B = V_S = 1200V$  $I_{FS}$ 10 uА HIN = LIN = 0V8.0 V<sub>BS</sub> quiescent supply current \_ 0.5 mA  $I_{BS}$ HIN = LIN = 0V 1.5  $I_{CC}$ V<sub>CC</sub> quiescent supply current 1.0 mΑ I<sub>O</sub> = 0A, HPOUT, LPOUT  $V_{OH}$ High level output voltage 14.5 V I<sub>O</sub> = 0A, HNOUT1, LNOUT1 0.5 ٧  $V_{OL}$ Low level output voltage \_  $V_{IH}$ High level input threshold voltage HIN, LIN, FO\_RST 2.2 3.0 4.0 V  $V_{IL}$ Low level input threshold voltage HIN, LIN, FO RST 0.6 1.5 2.1 V  $I_{\mathsf{IH}}$ High level input bias current  $V_{IN} = 5V$ 0.6 1.0 1.4 mΑ  $I_{\mathsf{IL}}$ Low level input bias current  $V_{IN} = 0V$ 0.00 0.00 0.01 mΑ HIN on-pulse 80 200 500 ns HIN off-pulse 80 200 500 ns LIN on-pulse 80 200 500 ns Input signals filter time tFilter LIN off-pulse 80 200 500 ns FO RST on-pulse 80 200 500 ns 80 200 500 FO off-pulse ns High side active Miller clamp NMOS input  $V_{IN} = 0V$ 20 5.0 V  $V_{HNO2}$ 3.4 threshold voltage Low side active Miller clamp NMOS input  $V_{LNO2}$  $V_{IN} = 0V$ 6.0 7.6 9.0 V threshold voltage  $tV_{NO2}$ Active Miller clamp NMOS filter time  $V_{IN} =$ 0V 400 ns  $V_{OLFO}$ Low level FO output voltage  $I_{FO} =$ 1mA 0.95 ٧  $V_{\text{IHFO}}$ High level FO input threshold voltage 4 0 2.2 3.0 V  $V_{ILFO}$ Low level FO input threshold voltage 0.6 1.5 2.1 V  $V_{\mathsf{BSuvr}}$ V<sub>BS</sub> supply UV reset voltage 10.5 11.3 12.1 ٧ 10.0 10.8  $V_{BSuvt}$ V<sub>BS</sub> supply UV trip voltage 11.6 ٧  $V_{\mathsf{BSuvh}}$ V<sub>BS</sub> supply UV hysteresis voltage  $V_{BSuvh} = V_{BSuvr} - V_{BSuvt}$ 0.2 0.5 8.0 V V<sub>BS</sub> supply UV filter time 4 8 16  $tV_{\mathsf{BSuv}}$ us  $V_{CIN}$ CIN trip voltage 0.40 0.50 0.60 ٧ 7.5 4.0 ٧  $V_{POR}$ POR trip voltage 5.5 Output high level short circuit pulsed HPOUT(LPOUT) = 0V,  $V_{IN}$  = 5V, PW  $\leq$  $I_{OH}$ 1 Α current  $HNOUT1(LNOUT1) = 15V, V_{IN} = 0V, PW$ Output low level short circuit pulsed current -1 Α loi 1 Active Miller clamp NMOS output low level HNOUT2(LNOUT2) = 15V, V<sub>IN</sub> = 0V, PW  $I_{OL2}$ -1 Α short circuit pulsed current ≤ 10us  $R_{OH}$ Output high level on resistance  $I_{O} = 1A, R_{OH} = (V_{OH} - V_{O})/I_{O}$ 15 Ω \_ \_ Ω R<sub>OL1</sub> Output low level on resistance  $I_0 = -1A$ ,  $R_{OL1} = V_0/I_0$ 15 Active Miller clamp NMOS output low level R<sub>OL2</sub>  $I_0 = -1A$ ,  $R_{OL2} = V_0/I_0$ 15 Ω on resistance HPOUT short to HNOUT1 and HNOUT2. tdLH(HO) 1.00 1.27 1.62 High side turn-on propagation delay us CL = 1nFHPOUT short to HNOUT1 and HNOUT2, 0.90 tdHL(HO) 1.21 1 47 High side turn-off propagation delay us CL = 1nFLPOUT short to LNOUT1 and LNOUT2, tdLH(LO) Low side turn-on propagation delay 1 00 1 39 1 90 us CL = 1nF LPOUT short to LNOUT1 and LNOUT2, 0.90 tdHL(LO) Low side turn-off propagation delay 1.19 1.70 us CL = 1nFtr Output turn-on rise time CL = 1nF 10 40 80 ns tf Output turn-off fall time CL = 1nF 10 40 80 Delay matching, high side turn-on and low DtdLH tdLH(HO)-tdHL(LO) -100 80 300 ns side turn-off Delay matching, high side turn-off and low DtdHL tdLH(LO)-tdHL(HO) -20 180 400 ns side turn-on Active clamp voltage  $V_{cc}$  – GND,  $V_{R}$  -  $V_{c}$ 24 ٧

Note: Typ is not specified

### **FUNCTION TABLE (Q: Keep previous status)**

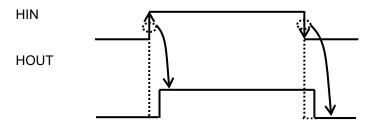
HIN	LIN	FO_RST	CIN	FO (Input)	V <sub>BS</sub> /	V <sub>cc</sub> / POR	HOUT	LOUT	FO (Output)	Behavioral status
L	L	L	L	-	Н	Н	L	L	Н	
L	Н	L	L	ı	Н	Н	L	Н	Н	
Н	L	L	L	ı	Η	Η	Н	L	Н	
Н	Н	L	L	ı	Н	н	Q	Q	Н	Interlock active
X	Н	Х	Н	ı	Х	Η	L	L	L	CIN tripping when LIN = H
Х	L	Х	Н	-	Х	Н	Q	Q	Н	CIN not tripping when LIN = L
Х	Х	Х	Х	L	Х	Η	L	L	-	Output shuts down when FO = L
Х	Х	Х	Х	-	Х	L	L	L	Н	V <sub>cc</sub> power reset
Х	L	L	L	-	L	Н	L	L	Н	V <sub>BS</sub> power reset
Х	Н	L	L	ı	L	Η	L	Н	Н	V <sub>BS</sub> power reset is tripping when LIN = H

Note1: "L" status of VBS/UV indicates a high side UV condition; "L" status of VCC/POR indicates a VCC power reset condition.

Note2: In the case of both input signals (HIN and LIN) are "H", output signals (HOUT and LOUT) keep previous status.

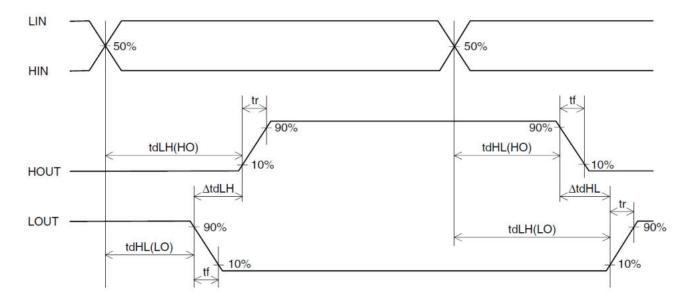
Note3 : X (HIN) :  $L\rightarrow H$  or  $H\rightarrow L$ . Other : H or L.

Note4: Output signal (HOUT) is triggered by the edge of input signal.



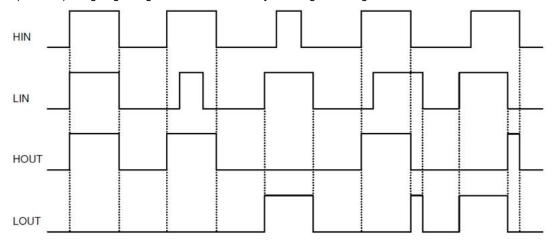
#### **FUNCTIONAL DESCRIPTION**

### 1. INPUT/OUTPUT TIMING DIAGRAM



#### 2. INPUT/OUTPUT TIMING DIAGRAM

When the input signals (HIN/LIN) are high level at the same time, the outputs (HOUT/LOUT) keep their previous status. But if signals (HIN/LIN) are going to high level simultaneously, HIN signals will get active and cause HOUT to enter "H" status.



Note1: The minimum input pulse width at HIN/LIN should be to more than 500ns (because of HIN/LIN input noise filter circuit).

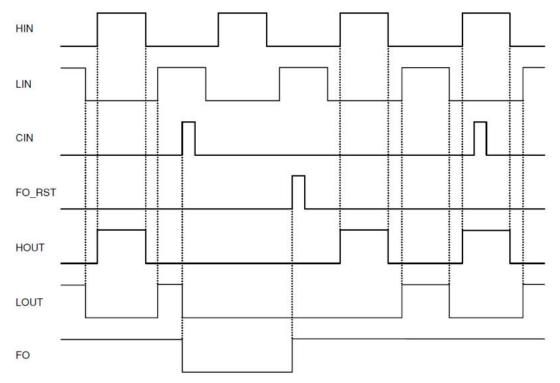
Note2: If a high-high status of input signals (HIN/LIN) is ended with only one input signal entering low level and another still being in high level, the output will enter high-low status after the delay match time (not shown in the figure above).

Note3: Delay times between input and output signals are not shown in the figure above.

#### 3. SHORT CIRCUIT PROTECTION TIMING DIAGRAM

When an over-current is detected by exceeding the threshold at the CIN and LIN is at high level at the same time, the short circuit protection will get active and shutdown the outputs while FO will issue a low level (indicating a fault signal).

The fault output latch is reset by a high level signal at FO\_RST pin and then FO will return to high level while the output of the driver will respond to the following active input signal.



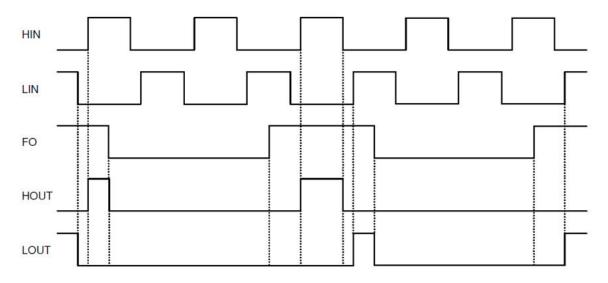
Note1: Delay times between input and output signals are not shown in the figure above.

Note2: The minimum FO\_RST pulse width should be more than 500ns (because of FO\_RST input filter circuit).

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#### 4. FO INPUT TIMING DIAGRAM

When FO is pulled down to low level in case the FO of other phases becomes low level (fault happened) or the MCU/DSP sets FO to low level, the outputs (HOUT, LOUT) of the driver will be shut down. As soon as FO goes high again, the output will respond to the following active input signal.

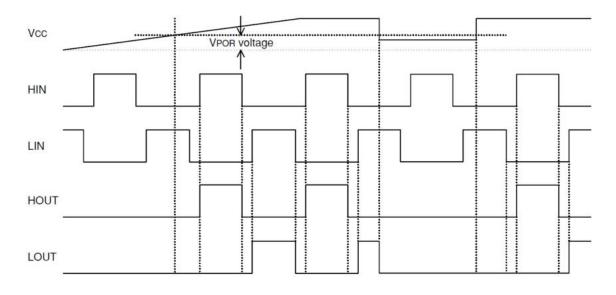


Note1: Delay times between input and output signals are not shown in the figure above.

Note2: The minimum FO pulse width should be more than 500ns (because of FO input filter circuit).

#### 5. LOW SIDE VCC SUPPLY POWER RESET SEQUENCE

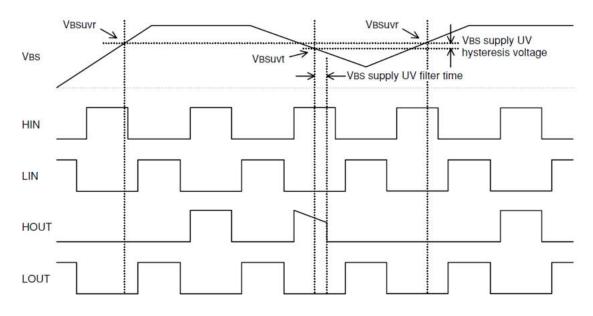
When the VCC supply voltage is lower than power reset trip voltage, the power reset gets active and the outputs (HOUT/LOUT) become "L". As soon as the VCC supply voltage goes higher than the power reset trip voltage, the outputs will respond to the following active input signals.



Note1: Delay times between input and output signals are not shown in the figure above

#### 6. HIGH SIDE VBS SUPPLY UNDER VOLTAGE LOCKOUT SEQUENCE

When VBS supply voltage drops below the VBS supply UV trip voltage and the duration in this status exceeds the VBS supply UV filter time, the output of the high side is locked. As soon as the VBS supply voltage rises above the VBS supply UV reset voltage, the output will respond to the following active HIN signal.

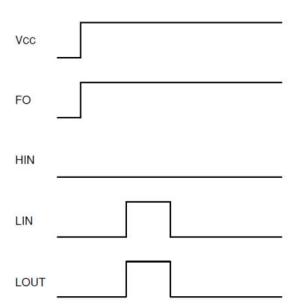


Note1: Delay times between input and output signals are not shown in the figure above.

#### 7. POWER START-UP SEQUENCE

At power supply start-up the following sequence is recommended when bootstrap supply topology is used.

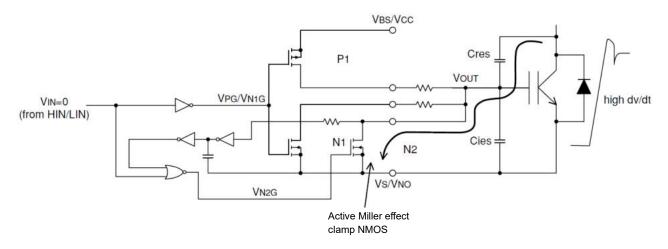
- ① Apply VCC.
- 2 Make sure that FO is at high level.
- ③ Set LIN to high level and HIN to low level so that bootstrap capacitor could be charged.
- 4 Set LIN to low level.



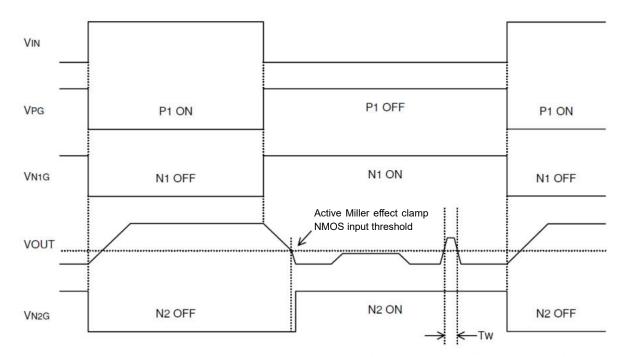
Note: If two power supply are used for supplying VCC and VBS individually, it is recommended to set VCC first and then set VBS.

#### 8. ACTIVE MILLER EFFECT CLAMP NMOS OUTPUT TIMING DIAGRAM

The structure of the output driver stage is shown in following figure. This circuit structure employs a solution for the problem of the Miller current through Cres in IGBT switching applications. Instead of driving the IGBT gate to a negative voltage to increase the safety margin, this circuit structure uses a NMOS to establish a low impedance path to prevent the self-turn-on due to the parasitic Miller capacitor in power switches.

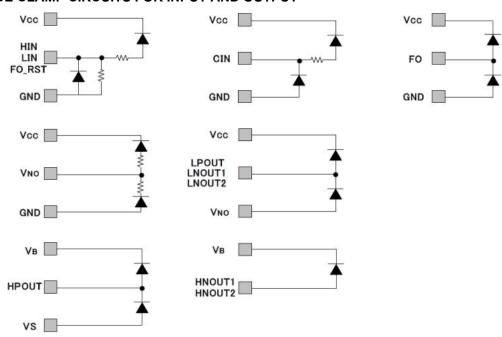


When HIN/LIN is at low level and the voltage of the VOUT (IGBT gate voltage) is below active Miller effect clamp NMOS input threshold voltage, the active Miller effect clamp NMOS is being turned on and opens a low resistive path for the Miller current through Cres.



Active Miller effect clamp NMOS keeps turn-on if Tw does not exceed active Miller clamp NMOS filter time

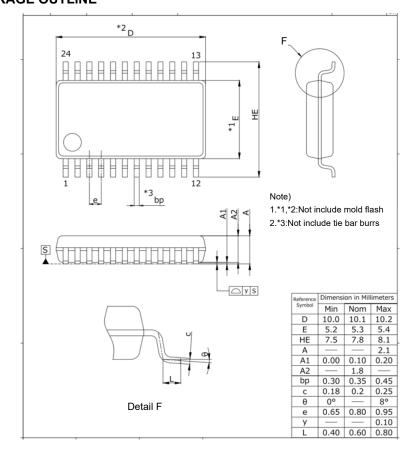
#### INTERNAL DIODE CLAMP CIRCUITS FOR INPUT AND OUTPUT

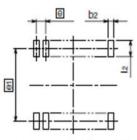


### **ENVIRONMENTAL CONSCIOUSNESS**

M81738FP is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU+(EU)2015/863.

### **PACKAGE OUTLINE**





Recommended Mount Pad

SYMBOLS	DIMENSIONS IN MILLIMETERS						
STIVIDOLS	MIN	NOM	MAX				
e1	_	7.62	_				
12	1.27	_	_				
е	_	0.8	_				
b2	_	0.5	_				

The above is one example.

Please design the mount pad with your evaluation.

### **Main Revision for this Edition**

		Revision			
Rev.	Date	Pages Points			
A	10 Jan. 2012	rayes -	New making		
^	10 0411. 2012	-	New making		
В	3 Dec. 2014	-	"PRELIMINARY" is deleted.		
		2	"TL" is added.		
		10	"ENVIRONMENTAL CONSCIOUSNESS" is added.		
С	19 Jun. 2019	4	Change V <sub>BSuvr</sub> for V <sub>BSuvt</sub>		
D	28 Apr. 2021	-	Update format		
Е	26 Jul. 2022	4	Change "W" to "Ω" about the unit of R <sub>OH</sub> , R <sub>OL1</sub> and R <sub>OL2</sub>		

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1200V HIGH VOLTAGE HALF BRIDGE DRIVER

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